In the Claims

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Cancel claims 11-25, without prejudice.

(Previously amended) A method for removing contaminate particulate matter from 1 1. 2 a contaminate particle containing substrate surface comprising the steps of: applying a sacrificial coating of a material to a substrate surface containing undesirable 3 particulate matter thereon, which material is to encapsulate and suspend the 4 undesirable particles therein; 5 6 fluidizing the material if necessary; 7 applying energy to the coated substrate to dislodge at least some of the particulate 8 matter from the surface of the substrate into the fluid sacrificial coating such that 9 the particulate matter is partially or fully encapsulated and suspended within the sacrificial coating forming a particulate matter containing sacrificial material 10 coating; 11 forming the fluidized particulate matter containing sacrificial material coating into a 12 strippable film; and 13 removing the particulate matter containing sacrificial material coating strippable film 14 from the substrate surface providing a substrate surface having less particulate 15 16 matter thereon.

2. (original) The method of claim 1 wherein the substrate is a semiconductor wafer.

(original) The method of claim 1 wherein the sacrificial coating material is a fluid. 1 3. (original) The method of claim 1 wherein the energy used is sonic energy. 1 4. (original) The method of claim 1 wherein the energy used is thermal, centrifugal, 1 2 magnetic or vibrational. (original) The method of claim 1 wherein the sacrificial coating material is a 1 6. liquid. 2 7. 1 (original) The method of claim 1 wherein the sacrificial coating material is a curable polymer. 2 8.-9. (canceled) 1 1 10. (original) The method of claim 1 wherein the material is a gas, liquid, vapor or fluid polymer. 2 11.-25. (Canceled) 1

- 1 26. (Previously added) The method of claim 1 wherein the strippable film is formed
- 2 simultaneously with application of the energy to dislodge the particles.